

**Search Notes**

Application/Control No.

10/815,909

Examiner

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Applicant(s)/Patent under  
Reexamination

SETO ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
710	52-57	11/1/2006	CS
370	229-236	11/1/2006	CS
370	464-468	11/1/2006	CS
710	29-38	6/18/2007	CS
710	52-57	6/18/2007	CS
710	71	6/18/2007	CS
710	306-313	6/18/2007	CS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	310,29,52	11/12/2007	CS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM for double patenting	11/1/2006	CS
EAST (USPGPUB, USOCR, USPAT, EPO, JPO, DERWENT, IBMTDB, USOCR)	11/1/2006	CS
EAST (USPGPUB, USOCR, USPAT, EPO, JPO, DERWNET, IBMTDB)	6/18/2007	CS
PLUS	6/18/2007	CS